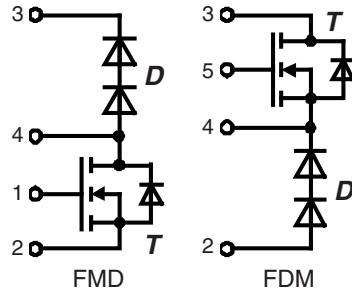
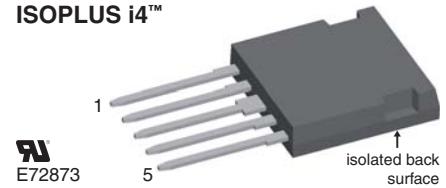


CoolMOS™¹⁾ Power MOSFET with HiPerDyn™ FRED Buck and Boost Topologies

Electrically isolated back surface
2500 V electrical isolation
N-Channel Enhancement Mode
Low $R_{DS(on)}$, high V_{DSS} MOSFET
Ultra low gate charge



I_{D25} = 47 A
 V_{DSS} = 600 V
 $R_{DS(on)\ max}$ = 0.045 Ω



MOSFET T

Symbol	Conditions	Maximum Ratings		
V_{DSS}	$T_{VJ} = 25^\circ\text{C}$	600	V	
V_{GS}		± 20	V	
I_{D25}	$T_C = 25^\circ\text{C}$	47	A	
I_{D90}	$T_C = 90^\circ\text{C}$	32	A	
E_{AS} E_{AR}	single pulse repetitive } $I_D = 11 \text{ A}; T_C = 25^\circ\text{C}$	1950	mJ	
dV/dt	MOSFET dV/dt ruggedness $V_{DS} = 0 \dots 480 \text{ V}$	50	V/ns	

Symbol Conditions Characteristic Values

($T_{VJ} = 25^\circ\text{C}$, unless otherwise specified)

		min.	typ.	max.	
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}; I_D = 44 \text{ A}$	40	45	$\text{m}\Omega$	
$V_{GS(\text{th})}$	$V_{DS} = V_{GS}; I_D = 3 \text{ mA}$	2.5	3	3.5	V
I_{DSS}	$V_{DS} = V_{DSS}; V_{GS} = 0 \text{ V}$	$T_{VJ} = 25^\circ\text{C}$	10	μA	
		$T_{VJ} = 125^\circ\text{C}$	50	μA	
I_{GSS}	$V_{GS} = \pm 20 \text{ V}; V_{DS} = 0 \text{ V}$		100	nA	
C_{iss} C_{oss}	$\left. \begin{array}{l} V_{GS} = 0 \text{ V}; V_{DS} = 100 \text{ V} \\ f = 1 \text{ MHz} \end{array} \right\}$	6800 320		pF pF	
Q_g Q_{gs} Q_{gd}	$\left. \begin{array}{l} V_{GS} = 0 \text{ to } 10 \text{ V}; V_{DS} = 400 \text{ V}; I_D = 44 \text{ A} \\ \end{array} \right\}$	150 35 50	190	nC nC nC	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f E_{on} E_{off} $E_{rec\ off}$	$\left. \begin{array}{l} V_{GS} = 10 \text{ V}; V_{DS} = 400 \text{ V} \\ I_D = 44 \text{ A}; R_G = 3.3 \Omega \end{array} \right\}$	30 20 100 10 tbd tbd tbd		ns ns ns ns mJ mJ mJ	
R_{thJC} R_{thCH}	with heat transfer paste	0.25	0.45	K/W K/W	

Features

- Silicon chip on Direct-Copper-Bond substrate
 - high power dissipation
 - isolated mounting surface
 - 2500 V electrical isolation
 - low drain to tab capacitance (< 40 pF)
- Fast CoolMOS™¹⁾ power MOSFET 4th generation
 - high blocking capability
 - lowest resistance
 - avalanche rated for unclamped inductive switching (UIS)
 - low thermal resistance due to reduced chip thickness
- Enhanced total power density
- HiPerDyn™ FRED
 - consisting of series connected diodes
 - enhanced dynamic behaviour for high frequency operation

Applications

- Switched mode power supplies (SMPS)
- Uninterruptible power supplies (UPS)
- Power factor correction (PFC)

Advantages

- Easy assembly:
no screws or isolation foils required
- Space savings
- High power density
- High reliability

¹⁾ CoolMOS™ is a trademark of Infineon Technologies AG.

MOSFET T Source-Drain Diode

Symbol	Conditions	Characteristic Values		
		(T _{VJ} = 25°C, unless otherwise specified)		
		min.	typ.	max.
I _S	V _{GS} = 0 V			44 A
V _{SD}	I _F = 44 A; V _{GS} = 0 V	0.9	1.2	V
t _{rr}		600		ns
Q _{RM}	I _F = 44 A; -di _F /dt = 100 A/μs; V _R = 400 V	17		μC
I _{RM}		60		A

Diode D (data for series connection)

Symbol	Conditions	Maximum Ratings				
V _{RRM}	T _{VJ} = 25°C to 150°C	600		V		
I _{F25}	T _C = 25°C	95		A		
I _{F90}	T _C = 90°C	56		A		
Symbol	Conditions	Characteristic Values				
		min.	typ.	max.		
V _F						
I _F = 30 A			T _{VJ} = 25°C	2.48 V		
I _F = 60 A				3.02 V		
I _F = 30 A			T _{VJ} = 150°C	1.89 A		
I _F = 60 A				2.45 A		
I _R			T _{VJ} = 25°C	1 μA		
I _R			T _{VJ} = 150°C	0.2 mA		
I _{FSM}			T _{VJ} = 45°C	450 A		
I _{RM} t _{rr}	I _F = 30 A; V _R = 100 V; -di _F /dt = 200 A/μs	T _{VJ} = 25°C		2 A		
				30 ns		
R _{thJC}				0.55 K/W		
R _{thCH}			with heat transfer paste	0.25 K/W		

Component

Symbol	Conditions	Maximum Ratings		
T _{VJ}	operating	-55...+150		°C
T _{stg}	storage	-55...+125		°C
V _{ISOL}	I _{ISOL} < 1 mA; 50/60 Hz	2500		V~
F _c	mounting force with clip	20...120		N

Symbol	Conditions	Characteristic Values		
		min.	typ.	max.
C _P	coupling capacity between shorted pins and mounting tab in the case	40		pF
d _S , d _A	pin - pin	1.7		mm
d _S , d _A	pin - backside metal	5.5		mm
Weight		9		g

ISOPLUS i4™ Outline

